

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

	User Part Number						
	PDTD123YT-Q						
boratory	Part Description						
	Nexperia DHAM Small Signal Bipolar Transistor						
iability labs	SMD package						
EC-Q101 Test	Test Conditions	Duration	# Lots	# Quantity	# Rejects		
TEST							
Pre- and Post-Stress							
Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
	JESD22-A113						
	Bake Tamb = 125 °C	24 hours					
Preconditioning		3 cycles	1674	70490	0		
		1000 hours	41E	10600	0		
Bid3	Teverse voltage	1000 110015	415	10000	U		
TC	IFSD22-A104						
Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	343	15360	0		
, , ,	- ,	1000 0,000	5.5	10000			
UHAST	JESD22-A118						
Unbiased HAST	Tamb = 130 °C, RH = 85 %	— 96 hours	362	15920	0		
	JESD22-A102						
AC	Tamb = 121 °C, RH = 100 %						
Autoclave	Pressure = 205 kPa (29.7 psia)						
H3TRB							
Temperature Reverse Bias		1000 hours	343	15360	0		
				.====	_		
intermittent Operating Life	100 C for 13000 cycles	1000 hours	343	15360	0		
DCH	IESD22-A111						
		10.6	263	8400	0		
	200 0 = 0 0	10.5	203	0430	U		
30							
į	Pre- and Post-Stress Electrical Test PC Preconditioning HTRB High Temperature Reverse Bias TC Temperature Cycling UHAST Unbiased HAST AC Autoclave H3TRB High Humidity High Temperature Reverse Bias IOL Intermittent Operating Life	PDTD123YT-Q boratory Part Description Nexperia DHAM SMD package EC-Q101 Test Test Conditions TEST Pre- and Post-Stress Electrical Test Tamb = 25 °C PC Soak Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Preconditioning PTRB MI039 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage TC JESD22-A104 Temperature Cycling TC JESD22-A104 Temperature Cycling TC JESD22-A104 Temperature Cycling TC JESD22-A104 Temperature Cycling AC JESD22-A102 AC JESD22-A102 AC JESD22-A102 AC JESD22-A102 AC JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia) H3TRB High Humidity High Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage IOL MIL-STD-750 Method 1037 Ton = toff, devices powered to insure ΔTj = 100 °C for 15000 cycles RSH Resistance to Solder Heat JESD22-A111	PDTD123YT-Q Part Description Nexperia DHAM Small Signal Islability labs SMD package	PDTD123YT-Q Part Description Nexperia DHAM Small Signal Bipolar Transist SMD package SMD package SMD package Test Conditions Duration # Lots Lots TEST Pre- and Post-Stress Electrical Test Tamb = 25 °C N/A see below Sake Tamb = 125 °C 24 hours 168 hours 168 hours 1674 N/A See Delow N/A	PDTD123YT-Q Part Description Nexperia DHAM Small Signal Bipolar Transistor Iability labs SMD package		

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia	Small Signal Bipolar				
DHAM	Transistor	18680	0	0,23	4,40E+09

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